KH7700 Quartz Crystals Temperature Test System

with
PI - network Measurement



New State of the Art Features

- Multi-Tasking operation in Microsoft Windows® allows testing in background while generating reports and graphs by operator
- Test limits such as Temperature range and ppm can be changed after actual testing, this gives better reports and graphs presentation for customers
- Support both "Direct impedance measure" & "Phy. CL " for FL measurement (Optional Phy CL head)
- User Programmable Drive Level: 10nW 1mW (max and min power depends on Rr of crystal)
- Crystal Measurement through passive π network techniques with KH1800 / KH1820 network analyzer
- Multiple crystal types may be accommodated in the same temperature run
- Automatic C0 cancellation for high frequencies
- User friendly system operation including menu driven, mouse operation and easy system calibration
- Perform pass/fail testing to user specified limits
- Stacked dual row test wheels can hold up to 508 crystals per chamber (depends on crystal type)
- Measures: Fs, FL, Rs, CL, C0, C1, L1, Q, Ts, C0/C1, DF, DLD, Spurious scan, Fs/T, and FL/T
- Optional Chinese operating software
- Frequency Range : KH1800 : 1 120 MHz

KH1820: 1 - 240 MHz

Standard System Configuration

- KH1800 or KH1820 Crystal π Network Analyzer
- KH7700 System Operating Software & System Cabling
- KM5901 Switch Box
- Work table



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- KH7220 Chamber
- Dual Row π network test head and 4 inch cover
- Dual row test wheel (for 49U, 49S Leaded-type crystals)
- Industrial computer or Lenovo Computer (or compatible) with Windows® XP (From better performance, suggest to use Intel Core 2 Duo E4500 2.2 GHz or above with 1G RAM, USB port, PCI slot (For long card) with 3.3V & 5V.

System Options

- Dual Chamber, Multi-Task, Time sharing Testing
- Stacked Dual Row π Network Test Head and 8" cover
- Test Head & Disk Pallet (for SMD crystals 7050, 5032, 3225, 2520.....etc)
- Chinese Language Support

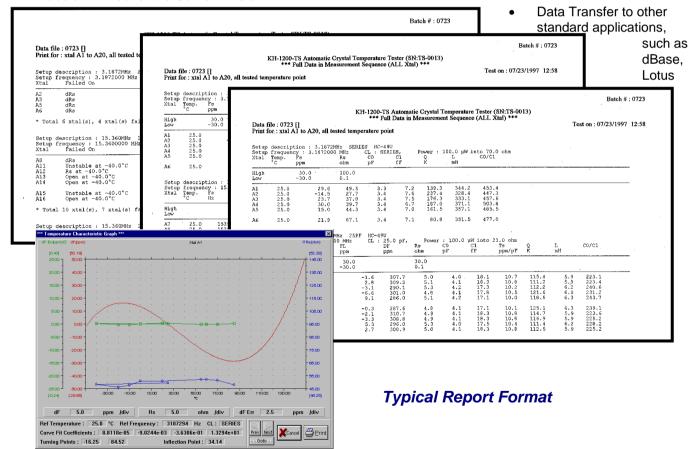
Software Capabilities

Easy Test Set up and Operation

• The user friendly Windows® environment eliminates the need of remembering how to operate or program a test.

Other Standard Reports

- Printout of Crystal Failures
- Printout of Crystal Measurements
- Printout of Frequency and Resistance vs. Temperature
- Plot of Frequency and Resistance vs. Temperature
- Tabular Printout of the Curve-fit Data



Specification herein are preliminary, and are subject to change without prior notice.

Photo shown is for reference only.

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